TOSHIBA TRANSISTOR SILICON NPN EPITAXIAL PLANAR TYPE

2 S C 5 0 9 3

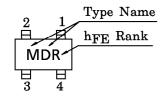
VHF~UHF BAND LOW NOISE AMPLIFIER APPLICATIONS

- Low Noise Figure, High Gain.
- NF=1.8dB, $|S_{21e}|^2$ =9.5dB (f=2GHz)

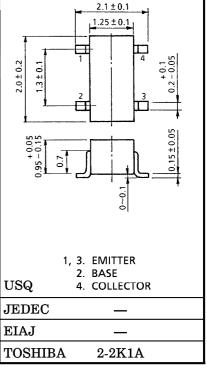
MAXIMUM RATINGS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	RATING	UNIT
Collector-Base Voltage	v_{CBO}	20	V
Collector-Emitter Voltage	v_{CEO}	10	V
Emitter-Base Voltage	$V_{ m EBO}$	1.5	V
Base Current	$I_{\mathbf{B}}$	20	mA
Collector Current	$I_{\mathbf{C}}$	40	mA
Collector Power Dissipation	$P_{\mathbf{C}}$	100	mW
Junction Temperature	T_{j}	125	°C
Storage Temperature Range	$\mathrm{T_{stg}}$	-55~125	°C

MARKING



Unit in mm



Weight: 0.006g

MICROWAVE CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Transition Frequency	$ m f_T$	$V_{CE}=8V, I_{C}=20mA$	7	10	_	GHz
Insertion Gain	$ S_{21e} ^2$ (1)	V_{CE} =8V, I_{C} =20mA, f=1GHz	12	15	_	dB
	$ S_{21e} ^2$ (2)	V_{CE} =8V, I_{C} =20mA, f =2GHz	6.5	9.5	_	ub
Noise Figure	NF (1)	$V_{CE}=8V$, $I_{C}=5mA$, $f=1GHz$	_	1.4	2.5	dB
	NF (2)	$V_{CE}=8V$, $I_{C}=5mA$, $f=2GHz$	_	1.8	3	иБ

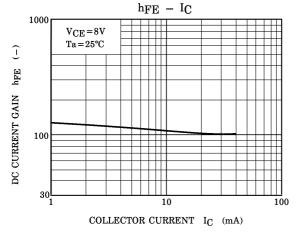
ELECTRICAL CHARACTERISTICS (Ta = 25°C)

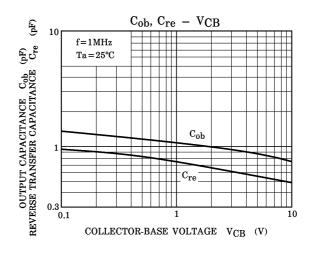
CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Collector Cut-off Current	I_{CBO}	$V_{CB} = 10V, I_{E} = 0$	_	_	1	μ A
Emitter Cut-off Current	I_{EBO}	$V_{EB}=1V, I_{C}=0$	_	_	1	μ A
DC Current Gain	hFE (Note 1)	$V_{CE}=8V, I_{C}=20mA$	50	_	160	_
Output Capacitance	$C_{f ob}$	$V_{CB} = 15V, I_{E} = 0, f = 1MHz$		0.65	1.05	рF
Reverse Transfer Capacitance	$\mathrm{C_{re}}$	(Note 2)	_	0.45	0.95	pF

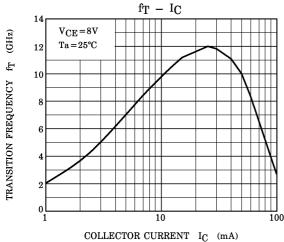
(Note 1) $~h_{\mbox{\scriptsize FE}}$ Classification ~R : 50~100, ~O : 80~160

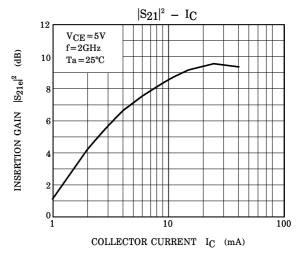
(Note 2) Cre is measured by 3 terminal method with capacitance bridge.

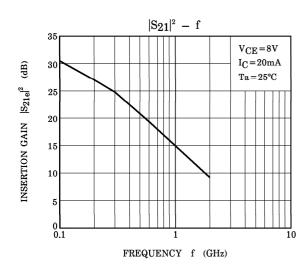
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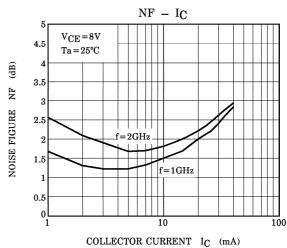




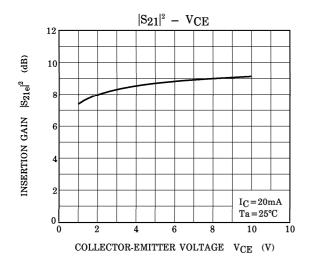


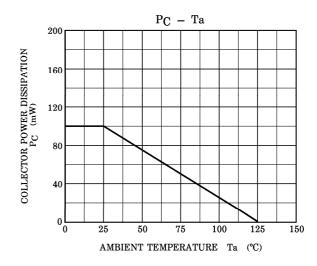






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S-Parameter $Z_O = 50\Omega$, $T_a = 25^{\circ}C$ $V_{CE} = 8V$, $I_C = 5mA$

frequency S1		11	S2	1	S1	S12		S22	
(MHz)	Mag.	Ang.	Mag.	Ang.	Mag.	Ang.	Mag.	Ang.	
200	0.801	-54.4	12.628	145.4	0.047	63.2	0.864	-32.2	
400	0.696	-95.6	9.664	121.9	0.072	48.8	0.675	-54.2	
600	0.617	-124.7	7.307	106.2	0.083	42.3	0.543	-68.4	
800	0.585	-146.3	5.779	95.1	0.090	39.3	0.456	-79.6	
1000	0.554	-163.0	4.674	86.8	0.095	39.5	0.400	-88.6	
1200	0.545	-176.5	3.902	80.0	0.099	40.4	0.357	-96.8	
1400	0.529	171.3	3.350	75.0	0.103	42.5	0.323	-104.5	
1600	0.529	161.1	2.929	70.0	0.108	44.8	0.299	-111.0	
1800	0.527	150.4	2.612	66.1	0.116	47.1	0.277	-116.5	
2000	0.513	141.0	2.366	62.1	0.122	49.6	0.258	-120.3	

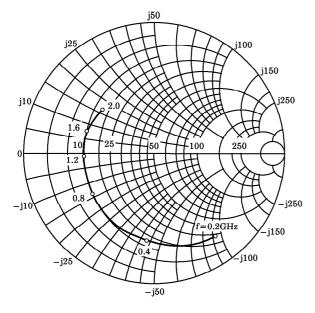
 $V_{CE} = 8V, I_{C} = 20mA$

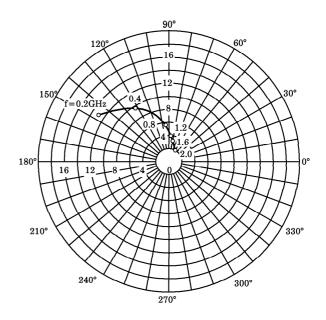
frequency	S11		S21		S12		S22	
(MHz)	Mag.	Ang.	Mag.	Ang.	Mag.	Ang.	Mag.	Ang.
200	0.556	-95.4	23.034	126.0	0.032	55.7	0.629	-53.5
400	0.521	-137.0	13.888	105.1	0.045	52.0	0.407	-75.8
600	0.505	-160.0	9.597	94.2	0.054	54.0	0.311	-89.3
800	0.505	-174.7	7.272	86.8	0.064	56.4	0.263	-101.3
1000	0.508	172.6	5.797	81.0	0.075	59.0	0.233	-112.0
1200	0.519	163.1	4.800	76.5	0.085	60.4	0.208	-122.9
1400	0.518	153.4	4.119	72.8	0.095	62.0	0.189	-132.7
1600	0.525	144.3	3.603	69.1	0.106	63.2	0.172	-141.7
1800	0.532	135.6	3.231	66.4	0.119	63.8	0.153	-149.3
2000	0.523	125.9	2.952	62.8	0.131	64.6	0.131	-153.9

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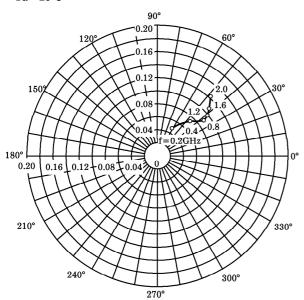
 $\begin{array}{l} S_{11e} \\ V_{CE} = 8V \\ I_{C} = 5 mA \\ Ta = 25 ^{\circ}C \\ (Unit: \Omega) \end{array}$

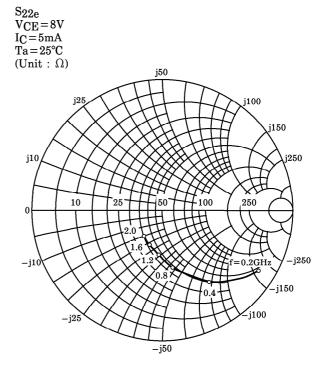






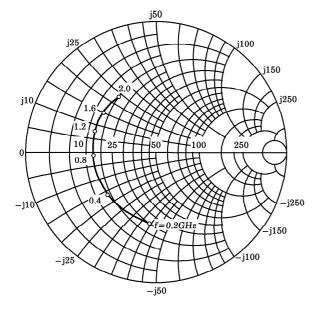
 $\begin{array}{c} S_{12e} \\ V_{CE} = 8V \\ I_{C} = 5 \text{mA} \\ Ta = 25 ^{\circ}\text{C} \end{array}$

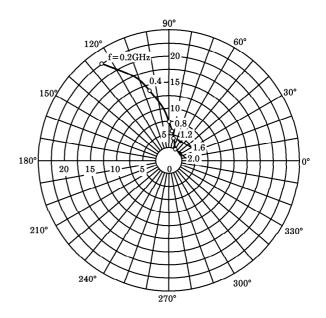




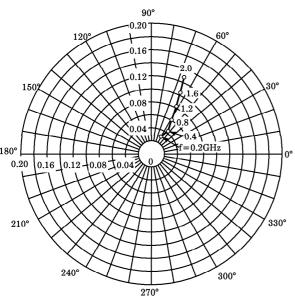
 $\begin{array}{l} S_{11e} \\ V_{CE} = 8V \\ I_{C} = 20 mA \\ Ta = 25 ^{\circ}C \\ (Unit: \Omega) \end{array}$

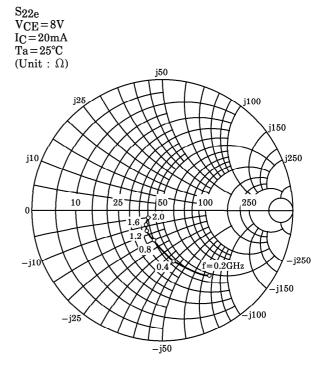






 $\begin{array}{l} S_{12e} \\ V_{CE} = 8V \\ I_{C} = 20 mA \\ Ta = 25 ^{\circ}C \end{array}$





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